

# UzADL method

# UzADL

- Unsupervised learning method
- Localize defected part
- Binary classification
- Principal stages:
  - Annotate unlabeled images
  - Train based on obtained images
  - Visualize defective regions

# Annonte unlabeled images

- Pre-Processing:
  - Represent images in 4D Tensor
  - $X \in \mathbb{R}^{M \times C \times H \times W}$ 
    - M: Total number of images
    - C: Number of channels
    - H: Image height
    - W: Image width
  - This tensor contains all the raw pixel values for the images.
  - Standardization of Pixel Values

# Pseudo-Labeling

- Want to label datas in 2 class (Normal – defected)
- Extract Features from the Images
- Construct the Graph Based on Feature Similarity
  - Create a graph of images
- Form the Adjacency Matrix and Degree Matrix
- Compute the Graph Laplacian Matrix
  - Degree matrix – adjacency matrix

$$\begin{pmatrix} M_1 & \dots & 0 \\ \vdots & \ddots & \vdots \\ 0 & \dots & M_K \end{pmatrix}$$

- Obtain the largest EVL and corresponding EVT
- Save into 1D vector
- Apply a threshold to classify On largest Eigenvectors( e.g. 0)
- Assign label to X0(class N) and X1(class A)

$$V_{GL} = \begin{bmatrix} 0.7 & 0 \\ -0.7 & 0 \\ 0 & 0.6 \\ 0 & -0.6 \end{bmatrix}$$

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**Input:** Tensor  $X_{std}$ ; **Output:**  $X_0, y_0, X_1, y_1$ ;

1: Let  $M_{Adj}$  be adjacent matrix of  $X_{std}$ ;

2: Obtain  $M_{Deg}$  based on  $M_{Adj}$ ;

3: Let  $M_{GL} = M_{Deg} - M_{Adj}$ ;

4: Obtain EVL and EVT of  $M_{GL}$ ;

5: Stack largest EVTs into  $V_{GL}$ ;

6: for  $i$  in  $len(V_{GL})$  do

7:   Cluster  $v_i$  into  $c_0$  and  $c_1$ ;

8: end for

$X_0 \leftarrow [], y_0 \leftarrow [], X_1 \leftarrow [], y_1 \leftarrow []$

9: for  $j$  in  $len(c_0)$  do

10:   Extend  $X_0$  with  $X == c_0[j]$ ;

11:   Extend  $y_0$  with 0;

12: end for

13: for  $k$  in  $len(c_1)$  do

14:   Extend  $X_1$  with  $X == c_1[k]$ ;

15:   Extend  $y_1$  with 1;

16: end for

17: Return  $X_0, y_0, X_1, y_1$ .

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# Training process

- Use pre-trained ResNet-18 model
- Extract features from the images
- After extracting the features, develop a model of several fully connected layers
- input of this model is the feature vector from ResNet-18.
- Use a sigmoid for last layer
- Use weighted binary cross-entropy loss function
- Use SGD optimizer

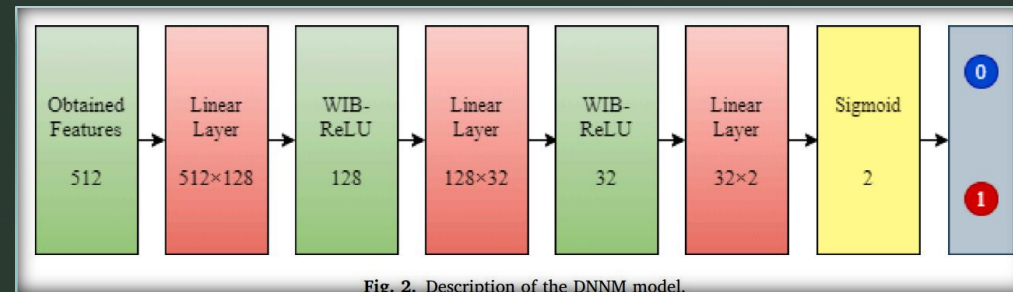
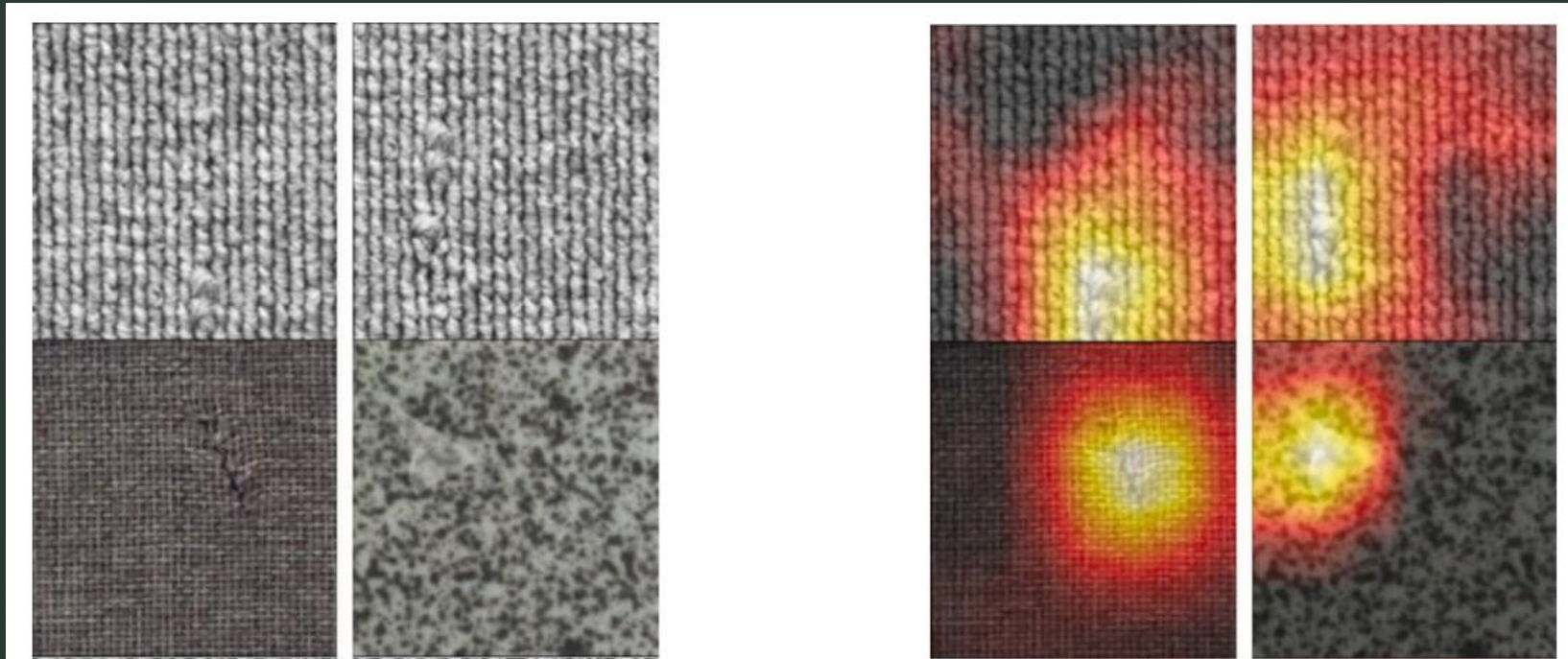


Fig. 2. Description of the DNNM model.

# Defect visualization

- If the model predicts an image as defected:
  - Compute significance of each feature map
    - partial derivative of the pre-final layer's output
  - It measures how sensitive the output is to changes in each feature map.
  - Apply Global Average Pooling On partial derivative
  - Result shows the importance of each feature map in defected class
  - heatmap highlights the regions in the image that contributed the most to the "defective" classification.

## Heatmap example





# Performance

Dataset Name	Model Name	AS	PS	RS	F1	AUC	Time (s)
NT	SSBD	0.942	0.926	0.978	0.952	0.870	2.034
	LDFC	0.958	0.932	<b>0.976</b>	0.954	0.886	1.901
	CTPT	0.937	0.944	0.948	0.946	0.892	1.972
	ADIC	0.832	0.819	0.829	0.824	0.792	4.281
	UNST	0.819	0.822	0.842	0.832	0.809	3.335
	UzADL	<b>0.984</b>	<b>0.971</b>	0.973	<b>0.972</b>	<b>0.899</b>	<b>1.224</b>
MVAD	SSBD	0.970	0.968	0.960	0.964	0.910	7.920
	LDFC	0.968	0.960	0.940	0.960	0.906	<b>5.240</b>
	CTPT	0.940	0.917	0.939	0.928	0.899	8.710
	ADIC	0.858	0.820	0.880	0.850	0.826	14.003
	UNST	0.892	0.865	0.835	0.850	0.843	12.827
	UzADL	<b>0.990</b>	<b>0.992</b>	<b>0.990</b>	<b>0.991</b>	<b>0.913</b>	7.164
DW	SSBD	0.972	0.921	0.939	0.930	0.892	8.802
	LDFC	0.980	0.899	<b>0.997</b>	0.948	0.905	9.124
	CTPT	0.958	0.962	0.938	0.950	0.899	9.120
	ADIC	0.903	0.895	0.891	0.893	0.850	19.573
	UNST	0.902	0.945	0.901	0.923	0.878	17.092
	UzADL	<b>0.996</b>	<b>0.997</b>	0.996	<b>0.996</b>	<b>0.946</b>	<b>5.530</b>